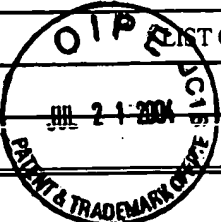
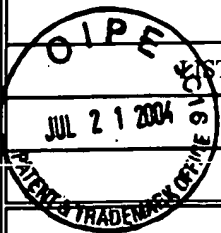


U.S. Department of Commerce, Patent and Trademark Office					Docket No.: 3816.06-C1			
					Serial No.: 10/829,641			
 LIST OF RELEVANT ART CITED BY APPLICANT (Use several sheets if necessary)					Applicant: Ranaan ZEHAVI et al.			
					Filing Date: April 22, 2004			
					Group: 2818			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
W	AA	5,492,229	02/2096	Tanaka et al.	211	41.18		
W	AB	5,516,283	05/14/96	Schrems	432	241		
W	AC	5,534,074	07/09/96	Koons	118	728		
W	AD	5,586,880	12/24/96	Ohsawa	432	241		
W	AE	5,595,604	01/21/97	Kobayashi et al.	118	715		
W	AF	5,752,609	05/19/98	Kato et al.	211	41.18		
W	AH	5,779,797	07/14/98	Kitano et al.	118	500		
W	AI	5,858,103	01/12/99	Nakajima et al.	118	728		
W	AJ	5,931,666	08/03/99	Hengest	432	258		
FOREIGN PATENT DOCUMENTS (Translation)								
		Document Number	Date	Country	Class	Subclass	Yes	No
W	AL	WO 00/21119	04/13/00	PCT			X	
W	AM	EP 0 884 769 A 1	12/16/98	Europe			X	
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR	anonymous, "Epi-II advanced Wafer," MEMC Applications Note, AE-003, March 2000, pp. 1-4						
	AS	anonymous, "Thin epi layers shown to improve gate oxide integrity performance," MEMC, date unknown, 1.p						
	AT							
Examiner <i>W. H. H. H.</i>			Date Considered <i>9-29-04</i>					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

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					Serial No.: 10/829,641			
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					Group: 2818			
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
MD	AA	6,065,615	05/23/00	Uchiyama et al.	211	41.18		
MD	AB	6,171,982	01/09/01	Sato	438	795		
MD	AC	6,180,497	01/30/01	Sato et al.	438	458		
MD	AD	6,284,997	09/04/01	Zehavi et al.	219	121.46		
MD	AE	6,450,346	09/17/02	Boyle et al.	219	41.18		
MD	AF	6,727,191	04/27/04	Zehavi et al.	438	795	12/23/98	
	AG							
	AH							
FOREIGN PATENT DOCUMENTS (Translation)								
		Document Number	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
Examiner <i>MD</i>			Date Considered <i>9-29-04</i>					
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